Search Notes

Application/Control	No
10/005,146	
Examiner	

lan dai thi truong

Applicant(s)/Patent under Reexamination MIYAZAWA, TAKEO Art Unit

	SEAR	CHED	
Class	Subclass	Date	Examiner
709	219		LDT

709	219	LDT
709	203	LDT

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH N (INCLUDING SEARC	HSTRATEGY	()
	DATE	EXMR
East search performance		LDT